Electronic Supplementary Material (ESI) for CrystEngComm.

Supplementary Information

Structural and electrical properties of lanthanum copper oxide epitaxial thin films with different domain morphologies

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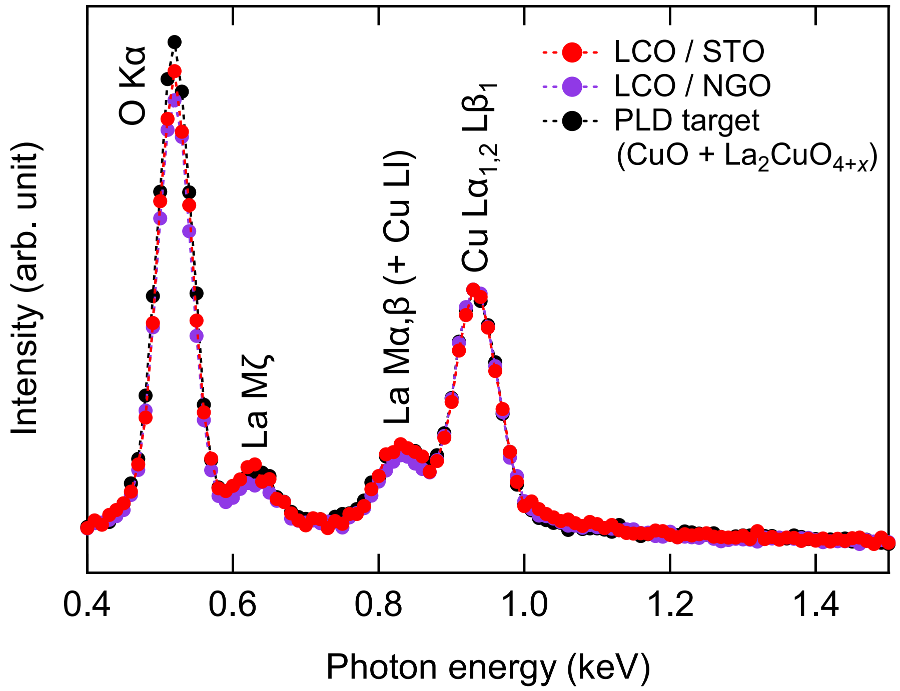

Figure S1. EDS spectra of the LCO films on STO (100) and NGO (110) substrates cooled under 30 Pa and the PLD target (mixture of CuO and La_2CuO_{4+x}). The spectra were normalized by the Cu $L\alpha_{1,2}L\beta_1$ peaks.

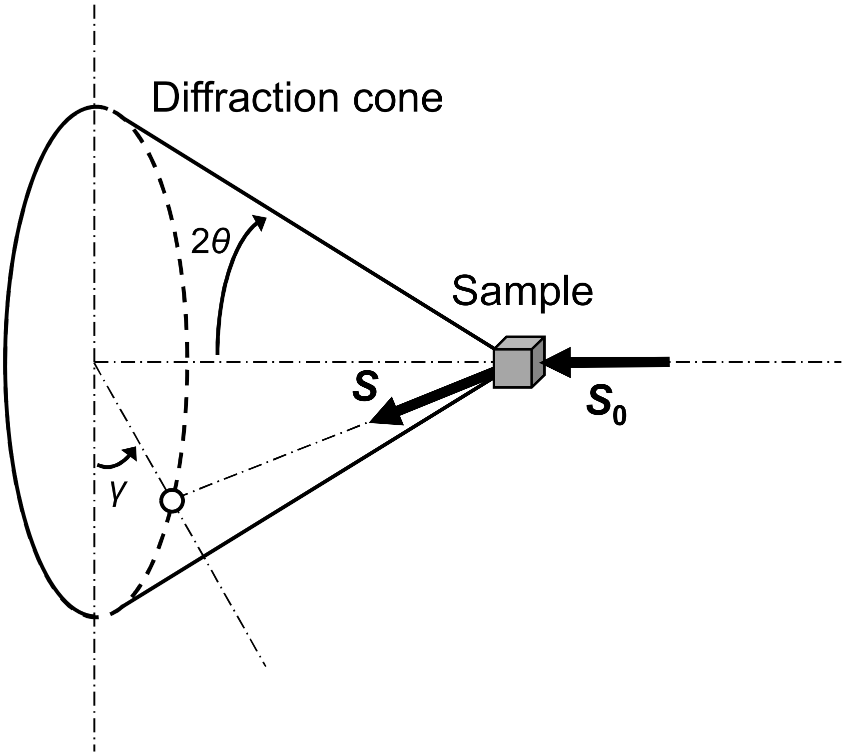

Figure S2. Diffraction cone and the definition of diffraction angles γ and 2θ. S_0 and S denote the direction of the incident and diffracted X-rays, respectively. Ref: B.B. He, *Powder Diffr.*, 2014, **29**, 113.